

Programme at a Glance

Wednesday 24th August 2022 <i>Power Modules and Manufacturing Processes</i>	Thursday 25th August 2022 <i>Dielectrics/Insulation and System Integration</i>	Friday 26th August 2022 <i>EMI, Control and Thermal/Reliability</i>
<p>0830 – 0930: <i>Packaging, Integration and Fast switching: what has been achieved and what's next?</i> Eckart Hoene, Fraunhofer</p> <p>0930 – 1030: <i>Paving the Way to Automotive GaN: The Importance of Packaging</i> Tamara Baksht, ViSiC</p> <p><i>1030 – 1100: Networking Break</i></p> <p>1100 – 1300: Power Modules</p> <p><i>1300 – 1400: Lunch</i></p> <p>1400 – 1600: Manufacturing Processes</p> <p>1600 – 1830: Poster Session</p> <p>1830 – 2000: Welcome Reception</p>	<p>0830 – 0930: <i>Insulation Materials and Systems for Power Modules: Challenges and Future</i> Mona Ghassemi, Virginia Tech</p> <p>0930 – 1030: <i>Environmental Trends and Challenges on Power Packaging</i> Chris Genthe, Rockwell Automation</p> <p><i>1030 – 1100: Networking Break</i></p> <p>1100 – 1300: Dielectrics and Insulation</p> <p><i>1300 – 1400: Lunch</i></p> <p>1400 – 1600: System Integration</p> <p><i>1730 – 2030: Dinner</i></p>	<p>0830 – 1030: <i>Electromagnetic Interference in Power Electronic Systems</i> Aaron Brovont, PC Krausse Associates</p> <p>0930 – 1030: <i>Reliability Trends in Power Electronics</i> Frede Blaabjerg and Francesco Iannuzzo, Aalborg University</p> <p><i>1030 – 1100: Networking Break</i></p> <p>1100 – 1300: Thermal Issues and Reliability</p> <p><i>1300 – 1400: Lunch</i></p> <p>1400 – 1600: EMI and Control</p> <p align="center">End of Workshop</p>

Session Speakers

Power Modules	Dielectrics and Insulation	Thermal and Reliability
<p><i>High Voltage Packaging for Diodes</i> Cyril Buttay, Laboratoire Ampère CNRS</p> <p><i>Protecting Power Semiconductors from H2S Gases</i> Bjoern Rentemeister, Infineon</p> <p><i>History of Power Module Design 1980s – 2020s (Virtual)</i> Reinhold Bayerer, Physics of Power Electronics Consulting</p>	<p><i>Development of Varnished Busbars</i> Michael Wingard, Amphenol</p> <p><i>Electric Field Grading in HV Integrated Systems: State-of-the-Art and Future Prospects</i> Sombel Diahm, Université de Toulouse</p>	<p><i>Thermo-Mechanical Constraints for Packaging of Diamond Components</i> Institute of Micro Electronics of Barcelona (IMB-CNM)</p> <p><i>On-Chip Junction Temperature Measurement using FBG Sensors</i> Sinisa Durovic, University of Manchester</p> <p><i>Mechanical Lifetime Testing of Wire-bonds vs. Power Cycling</i> Golta Khatibi, TU Wien</p> <p><i>Modular and Double-Sided Air-Cooled Power Module with Paralleled Switching Cells</i> Yvan Avenas, G2ELab</p>
Manufacturing Processes	System Integration	EMI and Control
<p><i>Liquid Metal Interconnections for Power Electronics</i> Nick Baker, University of Alabama</p> <p><i>Insights into the Layout of Power Semiconductor Chips</i> Peter Friedrichs, Infineon</p>	<p><i>Series Connected SiC MOSFETs Voltage Balancing: Two Methods with Adaptive Delays</i> Cedric Mathieu De Vienne, SuperGrid Institute</p>	<p><i>Auxiliary Circuit Design for 10kV SiC MOSFET Modules (Virtual)</i> Jun Wang, University of Nebraska-Lincoln</p> <p><i>Packaging Design for Low EMI Generation of Power Modules</i> Pierre-Olivier Jeannin, G2ELab</p>